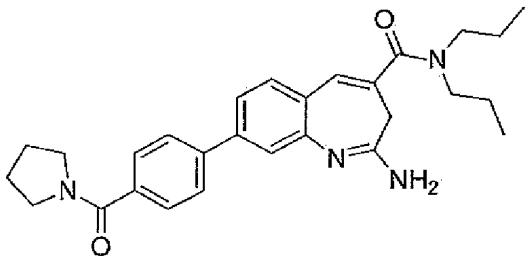
WHAT IS CLAIMED:

1. A crystalline form of the compound of formula (I):



(I).

2. The crystalline form of the compound of claim 1, wherein said crystalline form comprises an unsolvated crystalline form.

3. The crystalline form of the compound of formula (I) of claim 2, wherein said crystalline form is characterized by an X-ray powder diffraction pattern comprising angle 2θ peaks at about 11.9 ± 0.2, 16.4 ± 0.2, 18.5 ± 0.2, 20.9 ± 0.2, 21.2 ± 0.2, 21.6 ± 0.2, 23.0 ± 0.2, 23.5 ± 0.2, 24.2 ± 0.2, and 27.4 ± 0.2,

wherein said x-ray powder diffraction spectrum is obtained using a Cu Kα radiation source (1.54 Å).

4. The crystalline form of the compound of formula (I) of claim 3, characterized by an endothermic event with an onset temperature of about 199 °C and about 211 °C as measured by differential scanning calorimetry.

5. The crystalline form of the compound of formula (I) of claim 2, wherein said crystalline form is characterized by an X-ray powder diffraction pattern comprising angle 2θ peaks at about 11.0 ± 0.2, 14.9 ± 0.2, 18.0 ± 0.2, 19.1 ± 0.2, 21.0 ± 0.2, and 22.8 ± 0.2,

wherein said x-ray powder diffraction spectrum is obtained using a Cu Kα radiation source (1.54 Å).

6. The crystalline form of the compound of formula (I) of claim 5, characterized by an endothermic event with an onset temperature of about 211 °C as determined by differential scanning calorimetry.

7. The crystalline form of the compound of formula (I) of claim 2, wherein said crystalline form is characterized by an X-ray powder diffraction pattern comprising angle 2θ peaks at about 12.0 ± 0.2, 13.4 ± 0.2, 15.7 ± 0.2, 16.4 ± 0.2, 18.4 ± 0.2, 19.5 ± 0.2, 21.5 ± 0.2, 22.4 ± 0.2, 22.8 ± 0.2, 23.5 ± 0.2, and 24.2 ± 0.2,

wherein said x-ray powder diffraction spectrum is obtained using a Cu Kα radiation source (1.54 Å).

8. The crystalline form of the compound of formula (I) of claim 7, characterized by an endothermic event with an onset temperature of about 206 °C as determined by differential scanning calorimetry.

9. The crystalline form of the compound of formula (I) of claim 2, wherein said crystalline form is characterized by an X-ray powder diffraction pattern comprising angle 2θ peaks at about 11.0 ± 0.2, 15.3 ± 0.2, 15.6 ± 0.2, 17.5 ± 0.2, 18.9 ± 0.2, 20.0 ± 0.2, 21.1 ± 0.2, 22.1 ± 0.2, 24.6 ± 0.2, 25.1 ± 0.2, and 26.5 ± 0.2,

wherein said x-ray powder diffraction spectrum is obtained using a Cu Kα radiation source (1.54 Å).

10. The crystalline form of the compound of claim 1, wherein said crystalline form comprises a solvated crystalline form.

11. The crystalline form of the compound of claim 10, wherein said solvated crystalline form is selected from the group consisting of 1,4-dioxane solvate, dichloromethane solvate, chlorobenzene solvate, and trifluoroethanol solvate.

12. The 1,4-dioxane solvate of claim 11, wherein said crystalline form is characterized by an X-ray powder diffraction pattern comprising angle 2θ peaks at about 10.7 ± 0.2, 15.2 ± 0.2, 15.5 ± 0.2, 17.5 ± 0.2, 18.6 ± 0.2, 19.7 ± 0.2, 20.9 ± 0.2, 21.8 ± 0.2, 24.2 ± 0.2, 24.7 ± 0.2, and 26.4 ± 0.2,

wherein said x-ray powder diffraction spectrum is obtained using a Cu Kα radiation source (1.54 Å).

13. The 1,4-dioxane solvate of claim 12, characterized by an endothermic event with an onset temperature of about 94 °C and about 193 °C as determined by differential scanning calorimetry.

14. The dichloromethane solvate of claim 11, wherein said crystalline form is characterized by an X-ray powder diffraction pattern comprising angle 2θ peaks at about 15.6 ± 0.2, 22.0 ± 0.2, and 23.7 ± 0.2,

wherein said x-ray powder diffraction spectrum is obtained using a Cu Kα radiation source (1.54 Å).

15. The dichloromethane solvate of claim 14, characterized by an endothermic event with an onset temperature of about 205 °C as determined by differential scanning calorimetry.

16. The chlorobenzene solvate of claim 11, wherein said crystalline form is characterized by an X-ray powder diffraction pattern comprising angle 2θ peaks at about 8.8 ± 0.2, 17.7 ± 0.2, and 21.4 ± 0.2,

wherein said x-ray powder diffraction spectrum is obtained using a Cu Kα radiation source (1.54 Å).

17. The trifluoroethanol solvate of claim 11, wherein said crystalline form is characterized by an X-ray powder diffraction pattern comprising angle 2θ peaks at about 4.6 ± 0.2, 4.8 ± 0.2, 15.3 ± 0.2, 16.6 ± 0.2, 18.1 ± 0.2, and 22.9 ± 0.2,

wherein said x-ray powder diffraction spectrum is obtained using a Cu Kα radiation source (1.54 Å).

18. The trifluoroethanol solvate of claim 17, characterized by an endothermic event with an onset temperature of about 206 °C as determined by differential scanning calorimetry.

19. The trifluoroethanol solvate of claim 11, wherein said crystalline form is characterized by an X-ray powder diffraction pattern comprising angle 2θ peaks at about 12.3 ± 0.2, 14.8 ± 0.2, 16.4 ± 0.2, 18.5 ± 0.2, 19.3 ± 0.2, 19.6 ± 0.2, 20.3 ± 0.2, 21.1 ± 0.2, 22.1 ± 0.2, 22.5 ± 0.2, 23.2 ± 0.2, 24.1 ± 0.2, 25.4 ± 0.2, and 28.2 ± 0.2,

wherein said x-ray powder diffraction spectrum is obtained using a Cu Kα radiation source (1.54 Å).

20. The trifluoroethanol solvate of claim 19, characterized by an endothermic event with an onset temperature of about 110 °C as determined by differential scanning calorimetry.

21. A pharmaceutical composition comprising a crystalline form of the compound of formula (I) of claim 1 and a pharmaceutically acceptable excipient.

22. A crystalline form of the compound of formula (I) of claim 1 for use in agonizing Toll-like receptor 8 (TLR8).

23. A crystalline form of the compound of formula (I) of claim 1 for use in treating cancer.